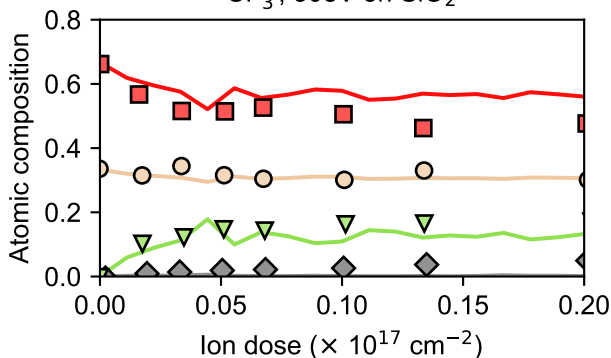
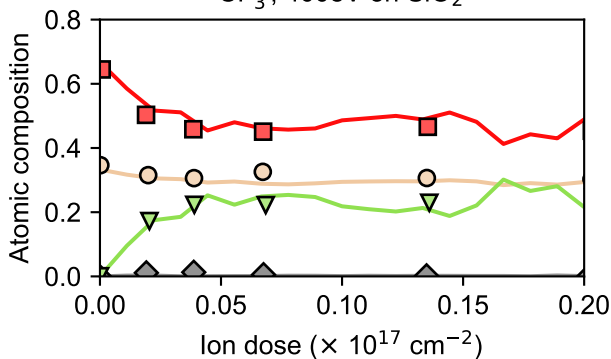


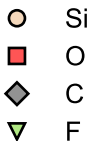
(a)

 CF_3^+ , 50eV on SiO_2 

(b)

 CF_3^+ , 400eV on SiO_2 

Toyoda et al.



This study

